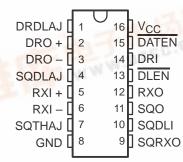
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- IEEE 802.3 1BASE5 Driver and Receiver
- On-Chip Receiver Squelch With Adjustable Threshold
- Adjustable Squelch Delay
- Direct TTL-Level Squelch Output
- Squelch Circuit Allows for External Noise Filtering
- Two Driver-Enable Options
- On-Chip Start-of-Idle Detection and Disable
- Driver Provides 2-V Minimum into a 50-Ω
 Differential Load Allowing for Use With Doubly-Terminated Lines and Multipoint Architectures
- On-Chip Driver Slew-Rate Control for Very Closely Matched Output Rise and Fall Times

N PACKAGE (TOP VIEW)



Function Tables

DRIVER

	INPUTS		OUT	PUTS
DRI	DATEN	DLEN	DRO +	DRO –
L	L	Χ	L	Н
Н	L	Χ	Н	L
X	Н	Н	Z	Z
Н	Н	L	H†	L†
L	Н	L	L‡	н‡

RECEIVER§

CONDITION	INPU	JTS	OUTPUTS		
CONDITION	RXI +	RXI –	RXO	SQO	
No active signal ¶	Х	Χ	Н	Н	
A ativo aignal ¶	L	Н	L	L	
Active signal ¶	Н	L	Н	L	

[†] This condition is valid during the time period set by DRDLAJ following a rising transition on DRI. Following this, when a subsequent positive transition does not occur on DRI, the outputs go to the high-impedance state.

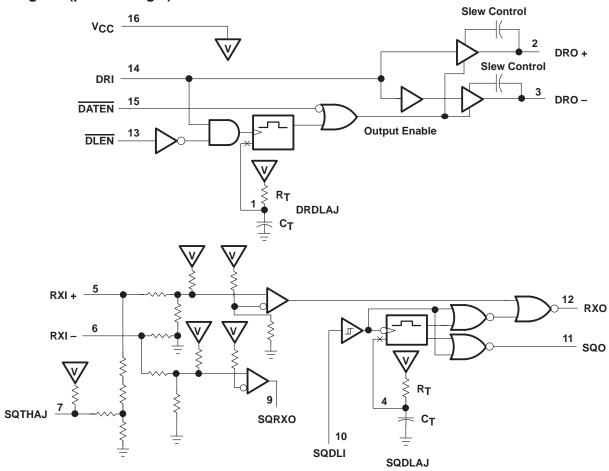


[‡] This condition is valid when it occurs within the enable time set by DRDLAJ after a rising transition on DRI. Otherwise, the outputs are in the high-impedance state.

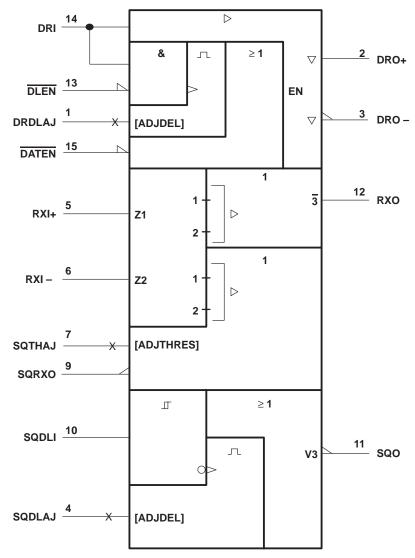
[§] Pins 9 and 10 are tied together.

[¶] An active signal is one that has an amplitude greater than the threshold level set by SQTHAJ.

logic diagram (positive logic)



logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

description

The SN75061 is a single-channel driver/receiver pair designed for use in IEEE 802.3, 1BASE5 applications as well as other general data communications circuits. The SN75061 offers both a driver and a receiver that are easily configured for use with a variety of controllers and data encoder/decoders.

The receiver features a full analog squelch circuit with an adjustable threshold and a programmable squelch delay. Internal nodes of the squelch circuitry are brought out to external connections to allow for the insertion of noise-filtering circuitry of the designer's choice.

As with the receiver, the driver offers a variety of implementation options. Driver enabling may be directly controlled by an external logic input or by use of an on-chip one-shot that is retriggered as long as data is being sent to the driver. The driver then automatically goes to the high-impedance state when end-of-packet common phrase occurs. The driver features internal slew-rate control for optimal matching of rise and fall times allowing for reduction of driver-induced jitter.



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receiver

The SN75061 receiver implements full analog squelch functions by integrating both a separate, parallel squelch receiver with an externally programmable threshold, and a programmable one-shot. The output of the squelch receiver and the input to the high-level, dc-triggered one-shot are brought out to external connections. These pins can be shorted for direct implementation or used for the insertion of noise-filtering circuitry of the implementer's design. The receiver one-shot can be effectively bypassed by applying a high logic level to SQDLI. The squelch threshold may be set externally by applying an external voltage set to a level that is –2 times the desired threshold voltage. When SQTHAJ is left open, the squelch receiver defaults to its internal preset value of –600 mV. The receiver also outputs a high logic squelch signal when there is not any active data present at the receiver inputs. When data is not present on the transmission line, the receiver output assumes a high level. The unsquelch duration is set externally with an R-C combination at SQDLAJ.

driver

The driver offers a variety of implementation options. Driver enabling may be controlled directly by an active-low, external logic input on $\overline{\text{DATEN}}$ or by use of another on-chip one-shot that retriggers with positive-going transitions on the driver input line. When positive transition does not occur within the pulse duration set by an external R-C combination, the one-shot times out and the driver is automatically put into a high-impedance state. When operating in the delay-enable mode, the 2-bit-time, high-level, start-of-idle pulse prescribed by IEEE 802.3 1BASE5 causes the one-shot to time out and automatically place the driver outputs in the high-impedance state. This delay time is also adjustable for use in other applications. The driver implements an output slew-rate control that is internally set for nominally 40 mV/ns. (This is roughly a 100-ns peak-to-peak differential transition time.) The driver outputs are capable of driving a 50- Ω differential load with a minimum output level of 2 V. Short-circuit output current is greater than 100 mA.



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Terminal Functions

PIN		DESCRIPTION
NAME	NO.	DESCRIPTION
DATEN	15	Driver data enable. When this sign is low, driver outputs are in an active state. When the signal is high, the driver outputs are in a high-impedance state when $\overline{\text{DLEN}}$ is also high.
DLEN	13	Driver delay enable. When this signal is low and DATEN is high, the driver outputs are active for a period of time set by DRDLAJ after a positive-going transition on DRI. When there is not any active data on DRI, the outputs are in a high-impedance state.
DRDLAJ	1	Driver delay adjust is a connection for the external R-C combination that determines the duration of the driver output active state after a positive transition on DRI when DLEN is low and DATEN is high.
DRI	14	Driver data input
DRO+	2	Noninverting driver output
DRO-	3	Inverting driver output
GND	8	Ground. Common for all voltages
RXI+	5	Noninverting receiver input
RXI-	6	Inverting receiver input
RXO	12	Main receiver input
SQDLAJ	4	Squelch delay adjust is a connection for an external R-C combination that determines the duration of the receiver unsquelch after a negative-going transition on SQDLI.
SQDLI	10	Squelch delay input is the input to the one-shot that controls the duration of the receiver unsquelch period. The main receiver output remains unsquelched as long as SQDLI is held high. Timing of the unsquelch period begins on the high-to-low transition of SQDLI.
SQO	11	Squelch output is high while the receiver is squelched.
SQRXO	9	Squelch receiver output is high only when the differential receiver input exceeds the threshold set by SQTHAJ.
SQTHAJ	7	Squelch receiver threshold adjust. The voltage at this input determines the threshold of the squelch receiver in a ratio of -2, SQTHAJ to threshold. When the receiver is left open, the squelch receiver threshold defaults to -600 mV.
Vcc	16	Supply-voltage input

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}	7 V
Input voltage, V _I (any logic input)	
Receiver differential input voltage	
Receiver input voltage	
Driver output voltage	0.5 V to 15 V
Continuous total dissipation at (or below) 25°C free-air temperature (see Note 1)	1150 mW
Operating free-air temperature range, T _A	0°C to 70°C
Storage temperature range, T _{stq}	–65°C to 150°C
Lead temperature 1.6 mm (1/16 inch) from case for 10 seconds	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: For operation above 25°C free-air temperature, derate to 736 mW at 70°C at the rate of 9.2 mW/°C.



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recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}	4.75	5	5.25	V
Driver high-level input voltage, VIH	2			V
Driver low-level input voltage, V _{IL}			0.8	V
Receiver common-mode input voltage, V _{IC} (see Note 2)	-2.5		5	V
Driver high-level output current, IOH			-150	mA
Driver low-level output current, IOL			150	mA
External timing resistance, R _{ext}	5		260	kΩ
External timing capacitance, C _{ext}	No	restriction	on	
Operating free-air temperature, T _A	0		70	°C

NOTE 2: The algebraic convention, in which the less-positive (more negative) limit is designated as minimum, is used in this data sheet for common-mode input voltage V_{IC} and threshold levels V_{IT+} and V_{IT+}.

electrical characteristics over recommended operating free-air temperature and supply voltage ranges (unless otherwise noted)

driver

	PARAMETER		TEST CONDITIONS		TYP [†]	MAX	UNIT
VIK	Input clamp voltage	$I_{I} = -18 \text{ mA}$				-1.5	V
\/o_=	$R_L = 50 \Omega$		2	2.4	3.3	V	
VOD	Differential output voltage	R _L = 115 Ω				3.65	V
ΔV _{OD}	Change in differential output voltage for a change in logic input state					50	mV
lн	High-level input current	V _I = 2 4 V				20	μΑ
I _{IL}	Low-level input current	V _I = 0.5 V		±100		-35	μΑ
los	Short-circuit output current	$V_{O} = 0 \text{ or } 6 \text{ V},$	$V_{I} = 0.8 \text{ V or } 2.5 \text{ V}$			±300	mA
lo-	High impodance output current	V00 = 5 25 V	V _{OC} = 10 V			100	^
loz	High-impedance output current	$V_{CC} = 5.25 \text{ V}$ $V_{OC} = 0$				-100	μА

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.



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electrical characteristics over recommended operating free-air temperature and supply voltage ranges (unless otherwise noted) (continued)

receiver

	PARAMETER		TEST Co	ONDITIONS	MIN	TYP [†]	MAX	UNIT
VIK	Input clamp voltage, squelch delay		I _I = -18 mA				-1.5	V
V _{IT+}	Positive-going input threshold volta	ge	$V_0 = 2.7 V$,	$I_0 = -0.4 \text{ mA}$			50	mV
V _{IT} _	Negative-going input threshold volt	age	$V_0 = 0.5 V$,	I _O = 16 mA	-50‡			mV
V _{hys}	Hysteresis voltage (V _{IT+} – V _{IT} _)					50		mV
VIC	Common-mode input voltage						5	V
		RXO	V _{CC} = 4.75 V,	I _{OH} = -400 μA,	2.7			
	I limb lavial autout valta aa	SQO	SQDLAJ at 0.8 V		2.7	3.5		V
VOH	High-level output voltage	SQRXO	$V_{CC} = 4.75 \text{ V},$ $V_{ID(RXI)} = -0.7 \text{ V},$	I _{OH} = -20 μA, SQDLAJ open	2.7	4.65		V
		RXO		I _{OL} = 8 mA			0.45	
	Low-level output voltage	SQO	V _{CC} = 4.75 V, SQDLAJ at 2 V	I _{OL} = 16 mA			0.5	V
VOL				$I_{OL} = 8 \text{ mA}$		0.35	0.5	
		SQRXO	$V_{CC} = 4.75 \text{ V},$ $V_{ID(RXI)} = 50 \text{ mV}$	I _{OL} = 8 mA			0.45	
		SQRXO		I _{OL} = 16 mA			0.5	
lн	High-level input current	SQDLI	V _I = 2.4 V				20	μΑ
I _I L	Low-level input current	JOUDLI	V _I = 0.5 V				-35	μΑ
		RXO	V 5 25 V	V _O = 0	-15		-85	
los	Short-circuit output current	SQO	V _{CC} = 5.25 V,	ΛΟ = 0	-15		-100	mA
		SQRXO	$V_{CC} = 5 V$,	V _O = 0	-0.8	-1	-1.2	
rį	Input resistance			_		10		kΩ
				V _{IC} = 1.5 V to 3.5 V	-525	-600	-675	mV
VIT-(sq)	Squelch preset input threshold voltage		V _{CC} = 5 V, SQTHAJ open	V _{IC} = -2.5 V to 1.5 V or 3.5 V to 5 V	-500		-700	mV
	Ratio of SQTHAJ input voltage to actual squelch threshold voltage		SQTHAJ at 200 mV	to 4 V	-1.9		-2.1	

driver and receiver

I _{CC} Supply current	V _{CC} = 5.25 V, Driver outputs disabled, No load	70	mA
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[†] All typical values are at V_{CC} = 5 V, T_A = 25°C. ‡ The algebraic convention, in which the less positive (more negative) limit is designated as minimum, is used in this data sheet for common-mode input voltage $V_{\mbox{\scriptsize IC}}$ and threshold levels $V_{\mbox{\scriptsize IT+}}$ and $V_{\mbox{\scriptsize IT-}}$.

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switching characteristics, V_{CC} = 5 V, T_A = 25°C

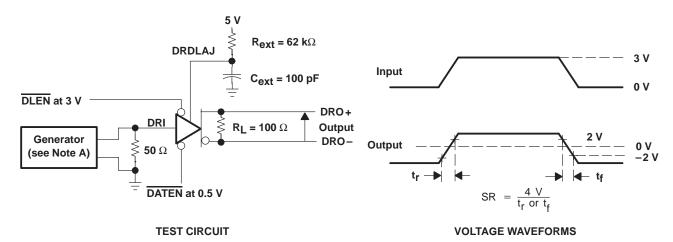
driver

	PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
SR	Differential-output slew rate	$V_O = -2 \text{ V to 2 V},$ $R_L = 100 \Omega \text{ (differential)},$	See Figure 1	28	40	52	mV/ns
td(OD)	Differential-output delay time $(t_d(OD)+ and t_d(OD)-)$	C_L = 15 pF, R_L =100 Ω (differential),	See Figure 2			160	ns
	Differential-output delay time difference (td(OD)+ - td(OD)-)	R_L =100 $Ω$ (differential),	See Figure 2			5	ns
^t PHZ	Disable time from DATEN					220	ns
tPLZ	Disable time from DATEN					300	ns
^t PZH	Fuchla time from DATEN	See Figure 3, 4, and 5				220	ns
tPZL	Enable time from DATEN					290	ns
^t PZH	Enable time from DLEN					250	ns
tw(en)	Enable pulse duration time (with DLEN low)	C _{ext} = 100 pF, See Figure 6	$R_{\text{ext}} = 62 \text{ k}\Omega,$	2	2.5	3	μs

receiver

	PARAMETER		TEST CONDITIONS		TYP	MAX	UNIT
ten(RX)	Receiver enable time	Squelch off,	See Figure 7		117		ns
t _{PLH}	Propagation delay time, low- to high level output	Squelch off,	See Figure 8		20	35	ns
tPHL	Propagation delay time, high- to low level output	Squelch off,	See Figure 8		22	35	ns
	Heavy slab dalay time	C _{ext} = 50 pF, See Figure 9	$R_{ext} = 51 \text{ k}\Omega,$	1	1.2	1.45	μs
^t d(unsq)		C _{ext} = 15 pF, See Figure 9	$R_{ext} = 6.8 \text{ k}\Omega,$			180	ns

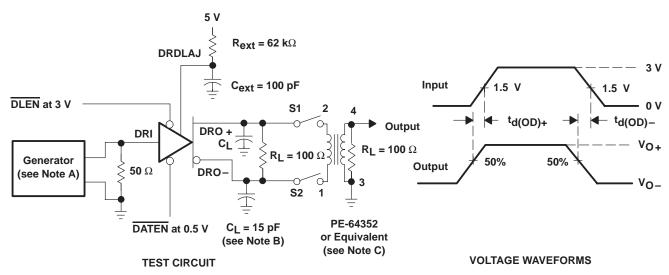
PARAMETER MEASUREMENT INFORMATION



NOTE A: The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, duty cycle \leq 50%, $t_f \leq$ 6 ns, $t_f \leq$ 8 ns, $t_f \leq$ 8 ns, $t_f \leq$ 9 ns, $t_$

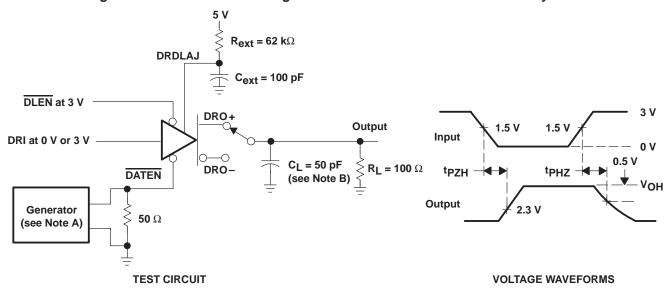
Figure 1. Test Circuit and Voltage Waveforms for Driver Slew Rate





- NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, duty cycle \leq 50%, $t_f \leq$ 6 ns, $t_f \leq$ 8 ns, $t_f \leq$ 8 ns, $t_f \leq$ 9 ns,
 - B. C_L includes probe and jig capacitance.
 - C. When measuring differential-output delay time difference, switches S1 and S2 are closed (Isolation transformer from Pulse Engineering P/N PE-64352).

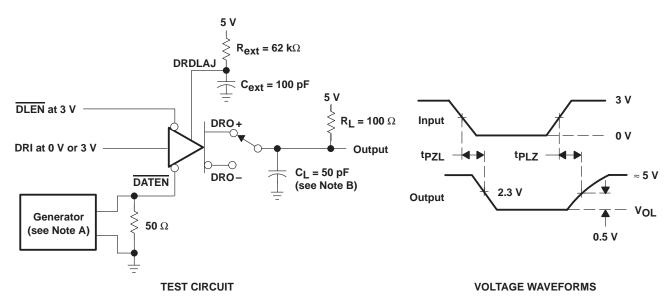
Figure 2. Test Circuit and Voltage Waveforms for Driver Differential Delay Time



- NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 500 kHz, duty cycle \leq 50%, $t_f \leq$ 6 ns, $t_f \leq$ 6 ns, $t_f \leq$ 0 ns,
 - B. C_I includes probe and jig capacitance.

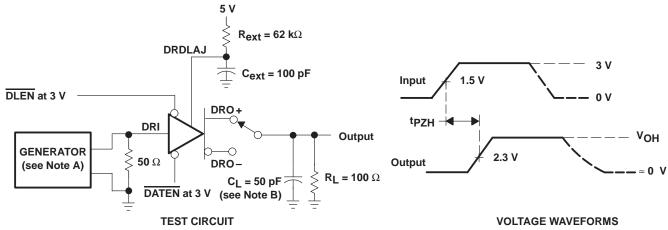
Figure 3. Test Circuit and Voltage Waveforms for Driver Enable and Disable Time





- NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 200 kHz, duty cycle \leq 50%, $t_{\Gamma} \leq$ 6 ns, $t_{f} \leq$ 6 ns, $t_{O} =$ 50 $t_{O} =$ 50
 - B. C_L includes probe and jig capacitance.

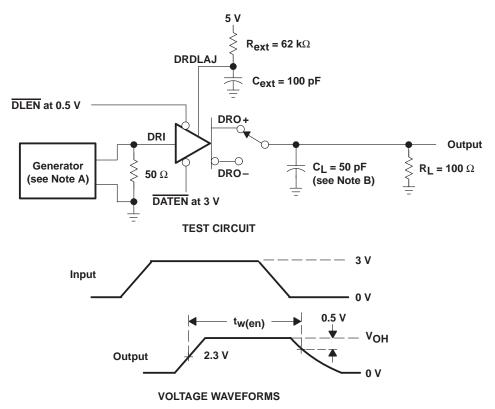
Figure 4. Test Circuit and Voltage Waveforms for Driver Enable and Disable Time



- NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, duty cycle \leq 50%, $t_f \leq$ 6 ns, $t_f \leq$ 8 ns, $t_f \leq$ 8 ns, $t_f \leq$ 8 ns, $t_f \leq$ 9 ns,
 - B. C_I includes probe and jig capacitance.

Figure 5. Test Circuit and Voltage Waveforms for Enable Time From Delay Enable

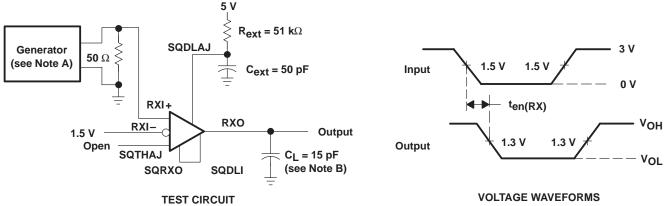




NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 200 kHz, duty cycle \leq 50%, $t_{f} \leq$ 6 ns, $t_{f} \leq$ 7 ns, $t_{f} \leq$ 8 n

B. C_L includes probe and jig capacitance.

Figure 6. Test Circuit and Voltage Waveforms for Enable Pulse Duration With Delay Enable Low

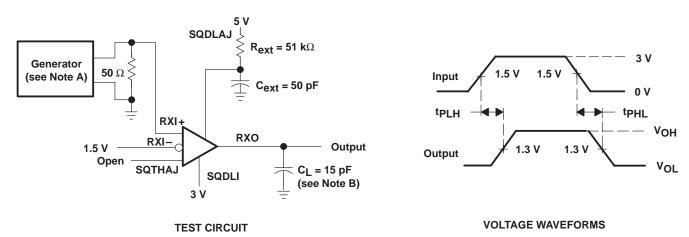


NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 500 kHz, duty cycle \leq 50%, $t_f \leq$ 6 ns, $t_f \leq$ 7 ns, $t_f \leq$ 8 ns,

B. C_L includes probe and jig capacitance.

Figure 7. Test Circuit and Voltage Waveforms for Receiver Enable (Unsquelch) Time





NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, duty cycle \leq 50%, $t_{f} \leq$ 6 ns, $t_{f} \leq$ 6 ns, $t_{Q} = 0.00$ $t_{Q} = 0.00$ $t_{Q} = 0.00$ $t_{Q} = 0.00$

B. CL includes probe and jig capacitance.

Figure 8. Test Circuit and Voltage Waveforms for Receiver Propagation Delay Time

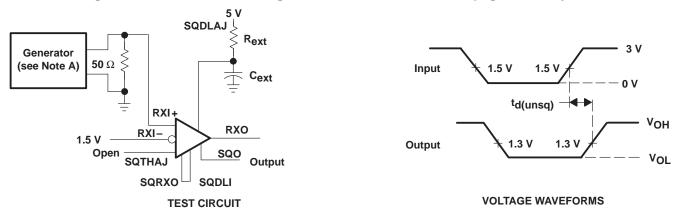


Figure 9. Test Circuit and Voltage Waveforms for Unsquelch Duration Time

NOTE A: The input pulse is supplied by a generator having the following characteristics: PRR \leq 100 kHz, duty cycle \leq 50%, $t_f \leq$ 6 ns, $t_f \leq$ 6 ns, $t_Q =$ 50 Ω .



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